



Dimension Upgrade

Huge Savings — Highest AFM Performance

Upgrading to Dimension Icon® or Dimension FastScan™ is now a cost-effective path for Dimension 3000, 3100 and 5000 users.

The new Dimension products feature the highest performance and greatest ease of use ever seen in an AFM.



● **Dimension Icon** – Today’s leading AFM performance with a path to all new Bruker AFM innovations:

- ScanAsyst® – simple operation with results previously achievable only by advanced users
- PeakForce QNM® - new sample information with nanoscale quantitative nano-mechanical mapping
- PeakForce KPFM™ - **New** quantitative, highest resolution workfunction measurements
- PeakForce TUNA™ - highest resolution current mapping on fragile samples in conjunction with mechanical information
- Glovebox Operation – electrical and electro-chemical nanoscale information with the greatest repeatability seen in any AFM with a 1PPM oxygen and water environment with PeakForce Tapping modes
- Electro Chemistry – the most complete ECAFM solution available; turnkey Lithium battery research
- PhotoConductive AFM - photoconductive studies (e.g., on OPVs) along with Bruker-unique electrical AFM modes
- Sample Heating and Cooling - temperature-gradient (-35°C to 250°C) studies with greatest precision

● **Dimension FastScan** – The revolutionary fast-scanning AFM with the greatest productivity ever seen in a AFM, and no sacrifice in resolution:

- The ultimate AFM with all the attributes of Dimension Icon, as well as ground-breaking technology to enable dynamics studies at the nanoscale
- Only large, tip-scanning AFM to scan at rates greater than 100Hz and render atomic resolution at greater than 5Hz scanning rates
- Comprehensive Materials, Electrical and Biological studies packages

With over 30 standard and proprietary AFM modes, the new Dimension instruments will ensure your research success!

For more information on how to trade up to the World’s Highest Performance AFM, please contact your Bruker representative at productinfo@bruker-nano.com

Atomic Force Microscopy

Innovation with Integrity